

**Search Notes**

Application/Control No.

10/507,066

Examiner

Benny Lee

Applicant(s)/Patent under  
Reexamination

YE, SHEN

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
333	99S,204, 219	10/18/2006	BTL
505	210,866	10/18/2006	BTL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR